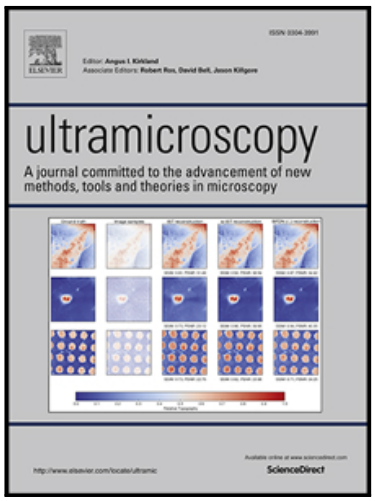

A consistent full-field integrated DIC framework for HR-EBSD

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Highlights

- A general, finite-strain Integrated DIC framework for HR-EBSD was developed.
- One-step correlation of the full field-of-view of EBSPs without filtering or remapping.
- High strain accuracy ($\sim 1 \times 10^{-5}$) for large rotations up to 10°, rivaling state-of-the-art HR-EBSD.
- High robustness / fast convergence from 1° misorientations with noise up to 20% / 5%.